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Time-measuring instruments — Photoluminescent deposits — Test methods and requirements

Instruments de mesure du temps — Dépôts photoluminescents — Méthodes d'essai et exigences

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Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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This document was prepared by Technical Committee ISO/TC 114, *Horology*, Subcommittee SC 5, *Luminescence*.

This second edition cancels and replaces the first edition (ISO 17514:2004), which has been technically revised.

The main changes are as follows:

- precisions have been added in the different test methods;
- the method of the ageing resistance test has been changed;
- in <u>4.2</u>, tests on components and on time-measuring instruments has been separated;
- adhesion tests (refers to ISO 3157 in ISO 17514:2004) have been added in this document.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at <u>www.iso.org/members.html</u>.

Introduction

Luminescent deposits on watch components (hands, dial, bezel) give the possibility to read the time in the dark. Radioluminescent deposits were common in the past but are not used anymore except for certain products under certain conditions which may be the subject of national regulations. Nowadays, photoluminescent products are mainly used. Their properties have been considerably improved these last years.

The present document describes test methods performed only on photoluminescent deposits, including some which were described in ISO 3157 and ISO 4168 concerning radioluminescent deposits, these standards having been withdrawn.

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